

**IN THE CLAIMS:**

1. (Currently Amended) For use with an integrated circuit (IC) having a testing port, a system for securing said IC as against subsequent reprogramming, comprising:

port inhibit circuitry located on said IC and modifiable to achieve a configuration that determines an extent to which said testing port is enabled, said extent selected from the group consisting of:

fully enabled,

only partially disabled, said partially disabled extent allowing a direct loopback between input and output pins of said testing port, and

completely disabled; and

port access circuitry, coupled to said testing port, that enables said testing port based on said configuration.

2. (Original) The system as recited in Claim 1 wherein said testing port is a Joint Test Action Group (JTAG) port.

3. (Original) The system as recited in Claim 1 wherein said port inhibit circuitry comprises an inhibit bit in a one-time programmable register.

4. (Original) The system as recited in Claim 1 wherein said port inhibit circuitry is configured to be permanently modified prior to delivering said IC to a user thereof.

5. Canceled

6. (Original) The system as recited in Claim 1 wherein said testing port comprises a direct loopback between input and output pins thereof.

7. (Original) The system as recited in Claim 1 wherein said IC is a baseband chip of a mobile communication device.

8. (Currently Amended) For use with an integrated circuit (IC) having a testing port, a method of securing said IC as against subsequent reprogramming, comprising:

modifying port inhibit circuitry located on said IC to achieve a configuration that determines an extent to which said testing port is enabled, said extent selected from the [[a]]group consisting of:

fully enabled,

only partially disabled, said partially disabled extent allowing a direct loopback between input and output pins of said testing port, and

completely disabled; and

enabling said testing port based on said configuration.

9. (Original) The method as recited in Claim 8 wherein said testing port is a Joint Test Action Group (JTAG) port.

10. (Original) The method as recited in Claim 8 wherein said port inhibit circuitry

comprises an inhibit bit in a one-time programmable register.

11. (Original) The method as recited in Claim 8 wherein said modifying comprises permanently modifying said port inhibit circuitry prior to delivering said IC to a user thereof.

12. Canceled

13. (Original) The method as recited in Claim 8 wherein said testing port comprises a direct loopback between input and output pins thereof.

14. (Original) The method as recited in Claim 8 wherein said IC is a baseband chip of a mobile communication device.

15. (Currently Amended) An electronic device, comprising:  
an integrated circuit (IC), including:  
a testing port,  
port inhibit circuitry located on said IC and modifiable to achieve a configuration that determines an extent to which said testing port is enabled, said extent selected from the group consisting:

fully enabled,

only partially disabled, said partially disabled extent allowing a direct loopback between input and output pins of said testing port, and

completely disabled; and

port access circuitry, coupled to said testing port, that enables said testing port based on said configuration.

16. (Original) The electronic device as recited in Claim 15 wherein said testing port is a Joint Test Action Group (JTAG) port.

17. (Original) The electronic device as recited in Claim 15 wherein said port inhibit circuitry comprises an inhibit bit in a one-time programmable register.

18. (Original) The electronic device as recited in Claim 15 wherein said port inhibit circuitry is configured to be permanently modified prior to delivering said IC to a user thereof.

19. Canceled

20. (Original) The electronic device as recited in Claim 15 wherein said electronic device is selected from the group consisting of:

a mobile telephone,

a PDA,

an MDA,

an MP3 player, and

a set-top box.